



**CHENMKO ENTERPRISE CO.,LTD**

Halogens free devices

**SMALL FLAT  
NPN Epitaxial Transistor**

VOLTAGE 25 Volts CURRENT 5 Ampere

**CHT200PGP**

**FEATURE**

- \* Small flat package. (DPAK)
- \* Low saturation voltage  $V_{CE(sat)}=0.3V$ (max.)( $I_C=500mA$ )
- \* High saturation current capability.

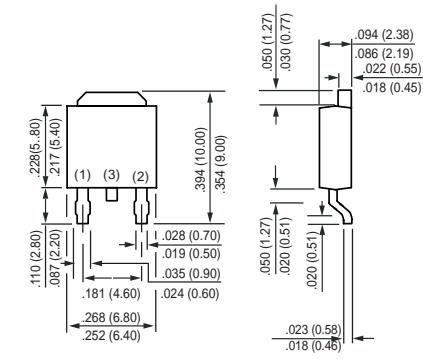
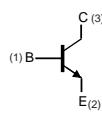
**CONSTRUCTION**

- \* NPN Switching Transistor



**DPAK**

**CIRCUIT**



**DPAK**

**MAXIMUM RATINGS** ( At  $T_A = 25^\circ\text{C}$  unless otherwise noted )

RATINGS	CONDITION	SYMBOL	MIN.	MAX.	UNITS
Collector - Base Voltage	Open Emitter	$V_{CBO}$	-	40	Volts
Collector - Emitter Voltage	Open Base	$V_{CEO}$	-	25	Volts
Emitter - Base Voltage	Open Collector	$V_{EBO}$	-	8	Volts
Collector Current DC		$I_C$	-	5	Amps
Peak Collector Current		$I_{CM}$	-	10	Amps
Peak Base Current		$I_{BM}$	-	1.0	Amps
Total Power Dissipation	$T_A \leq 25^\circ\text{C}$	$P_{TOT}$	-	1400	mW
Storage Temperature		$T_{STG}$	-55	+150	°C
Junction Temperature		$T_J$	-	+150	°C

## RATING CHARACTERISTIC CURVES ( CHT200PGP )

**CHARACTERISTICS ( At TA = 25°C unless otherwise noted )**

PARAMETERS	CONDITION	SYMBOL	MIN.	TYPE	MAX.	UNITS
Collector Cut-off Current	I <sub>E</sub> =0; V <sub>CB</sub> =40V	I <sub>CBO</sub>	-	-	0.1	uA
Emitter Cut-off Current	I <sub>C</sub> =0; V <sub>EB</sub> =8V	I <sub>EBO</sub>	-	-	0.1	uA
DC Current Gain	V <sub>CE</sub> =1V; Note 1 I <sub>C</sub> =500mA I <sub>C</sub> =2.0A I <sub>C</sub> =5.0A; V <sub>CE</sub> =2V	$h_{FE}$	70 45 10	- - -	- 180 -	
Collector-Emitter Saturation Voltage	I <sub>C</sub> =500mA; I <sub>B</sub> =50mA I <sub>C</sub> =2A; I <sub>B</sub> =200mA I <sub>C</sub> =5A; I <sub>B</sub> =1A	V <sub>CESat</sub>	- - -	- - -	0.3 0.75 1.8	Volts
Base-Emitter Saturatio Voltage	I <sub>C</sub> =5A; I <sub>B</sub> =1A	V <sub>BESat</sub>	-	-	2.5	Volts
Collector Capacitance	I <sub>E</sub> =I <sub>B</sub> =0; V <sub>CB</sub> =10V; f=0.1MHz	C <sub>c</sub>	-	-	80	pF
Transition Frequency	I <sub>C</sub> =0.1A; V <sub>CE</sub> =10V; f=10MHz	f <sub>T</sub>	65	-	-	MHz

**Note :**

- Pulse test: tp ≤ 300uSec; δ ≤ 0.02.